


Patent Agent

Viktor Simkovic

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Profile

Viktor Simkovic is a patent agent based in Fitch Even's Chicago office. He assists clients with U.S. patent application preparation and prosecution, including analyzing prior art, preparing applications, responses to USPTO office actions, and strategies for preparing continuing applications.

Viktor has experience working with clients in industries such as cellular wireless communication, networking devices, networking software, machine learning, vehicle telematics, medical imaging, petroleum testing, semiconductor manufacturing, and internet searching.

Before joining Fitch Even, Viktor worked as a patent agent at patent boutique firms in the DC area. Viktor also worked as a patent examiner at the United States Patent and Trademark Office, where he examined patent application in the semiconducting processing art. Prior to working as an examiner, Viktor worked on research in the field of chemical vapor deposition of thin films.

Viktor's combined experience has prepared him to anticipate challenges that may arise during the patent preparation and prosecution process, ensuring he can navigate each step with proficiency.

Representative Matters

- Assists with preparation of U.S. patent applications directed to aviation components for a global conglomerate.

Presentations + Publications

Publications

- "Novel Low Dielectric Constant Thin Film Materials by Chemical Vapor Deposition," Master's thesis, Virginia Tech, 1999.

Education

M.S., Materials Science and Engineering, Virginia Polytechnic Institute and State University, 1999

B.S., Materials Science and Engineering, Virginia Polytechnic Institute and State University, 1997

B.S., Mathematics, Virginia Polytechnic Institute and State University, 1997

Bar Admissions

U.S. Patent and Trademark Office

Services

International IP Protection

Patent Preparation + Prosecution

Industries

Computer Software + Hardware

Internet + E-Commerce

Material Science

- Senkevich, J. J., Simkovic, V., and Desu, S. B., “Optical Birefringence to Determine Morphological Changes in Low-K Thin Film CVD Polymers,” *MRS Online Proceedings Library*, vol. 511, Jan. 1998: 139-144.
- Senkevich, J. J., Desu, S. B., and Simkovic, V., “Temperature Studies of Optical Birefringence and X-ray Diffraction with Poly (p-xylylene), Poly (chloro-p-xylylene) and Poly (tetrafluoro-p-xylylene) CVD Thin Films,” *Polymer*, vol. 41, no. 7, 2000: 2379-2390.